



SCOPE OF ACCREDITATION TO ISO/IEC 17025-2005
& ANSI/NCSL Z540-1-1994 & ANSI/NCSL Z540.3

SIMCO ELECTRONICS
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CALIBRATION

Valid To: September 30, 2017

Certificate Number: 1395.22

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations and dimensional inspections¹:

I. Electrical – DC / Low Frequency

Parameter/Equipment	Range	CMC ^{2,5} (±)	Comments
DC Voltage – Generate ³	Up to 330 mV 330 mV to 3.3 V (3.3 to 33) V (33 to 330) V (330 to 1000) V	17 µV/V + 1 µV 10 µV/V + 1.6 µV 10 µV/V + 16 µV 15 µV/V + 117 µV 15 µV/V + 1.2 mV	Fluke 5520A
DC Voltage – Measure ³	(0 to 200) mV (0.2 to 2) V (2 to 20) V (20 to 200) V (200 to 1000) V	6.5 µV/V + 0.1 µV 4.1 µV/V + 0.4 µV 4.0 µV/V + 4 µV 5.8 µV/V + 40 µV 5.9 µV/V + 0.5 mV*	Fluke 8508A
DC Current – Generate ³	(0 to 330) µA 330 µA to 3.3 mA (3.3 to 33) mA (33 to 330) mA 330 mA to 1.1 A (1.1 to 3) A (3 to 11) A (11 to 20) A	0.012 % + 20 nA 80 µA/A + 40 nA 80 µA/A + 0.19 µA 80 µA/A + 2 µA 0.016 % + 32 µA 0.030 % + 32 µA 0.040 % + 0.39 mA 0.078 % + 0.59 mA	Fluke 5520A Fluke 5520A/SC1100
Clamp Meters	(0 to 1000) A	0.39 % + 0.06A	Fluke 5500A/coil & 5520A/SC1100

Parameter/Equipment	Range	CMC ^{2,5} (\pm)	Comments
DC Current – Measure ³	(0 to 200) μ A (0.2 to 20) mA (20 to 200) mA (0.2 to 2) A (2 to 20) A (20 to 100) A	13 μ A/A + 0.4 nA 15 μ A/A + 40 nA 49 μ A/A + 0.8 μ A 0.019 % + 16 μ A 0.042 % + 0.4 mA 0.058 % + 10 μ A	Fluke 8508A Valhalla 2575A w/ 8508A
Resistance – Generate ³	Up to 11 Ω (11 to 33) Ω (33 to 110) Ω (110 to 330) Ω (0.33 to 1.1) k Ω (1.1 to 3.3) k Ω (3.3 to 11) k Ω (11 to 33) k Ω (33 to 110) k Ω (110 to 330) k Ω (0.33 to 1.1) M Ω (1.1 to 3.3) M Ω (3.3 to 11) M Ω (11 to 33) M Ω (33 to 110) M Ω (110 to 330) M Ω (0.33 to 1.1) G Ω	33 $\mu\Omega/\Omega$ + 7.8 m Ω 26 $\mu\Omega/\Omega$ + 12 m Ω 27 $\mu\Omega/\Omega$ + 12 m Ω 30 $\mu\Omega/\Omega$ + 16 m Ω 27 $\mu\Omega/\Omega$ + 16 m Ω 30 $\mu\Omega/\Omega$ + 0.16 Ω 34 $\mu\Omega/\Omega$ + 78 m Ω 27 $\mu\Omega/\Omega$ + 0.78 Ω 25 $\mu\Omega/\Omega$ + 0.78 Ω 27 $\mu\Omega/\Omega$ + 7.8 Ω 30 $\mu\Omega/\Omega$ + 7.8 Ω 48 $\mu\Omega/\Omega$ + 0.12 k Ω 0.011 % + 0.2 k Ω 0.020 % + 1.9 k Ω 0.039 % + 2.3 k Ω 0.24 % + 78 k Ω 1.2 % + 0.4 M Ω	Fluke 5520A/SC1100
Resistance – Measure ³	Up to 2 Ω (2 to 20) Ω (20 to 200) Ω (0.2 to 2) k Ω (2 to 20) k Ω (20 to 200) k Ω (0.2 to 2) M Ω (2 to 20) M Ω (20 to 200) M Ω (0.2 to 2) G Ω	20 $\mu\Omega/\Omega$ + 4 $\mu\Omega$ 11 $\mu\Omega/\Omega$ + 14 $\mu\Omega$ 8.7 $\mu\Omega/\Omega$ + 50 $\mu\Omega$ 8.6 $\mu\Omega/\Omega$ + 500 $\mu\Omega$ 8.6 $\mu\Omega/\Omega$ + 5 m Ω 8.8 $\mu\Omega/\Omega$ + 50 m Ω 11 $\mu\Omega/\Omega$ + 1 Ω 24 $\mu\Omega/\Omega$ + 0.1 k Ω 80 $\mu\Omega/\Omega$ + 1 k Ω 0.022 % + 0.1 M Ω	Fluke 8508A HiV



Parameter/Equipment	Range	CMC ^{2,5} (±)	Comments	
Capacitance – Generate ³				
10 Hz to 10 KHz	(0.19 to 0.3999) nF	0.55 % + 7.8 pF	Fluke 5520A	
10 Hz to 10 KHz	(0.4 to 1.0999) nF	0.44 % + 7.8 pF		
10 Hz to 3 KHz	(1.1 to 3.2999) nF	0.42 % + 7.8 pF		
10 Hz to 1 KHz	(3.3 to 10.9999) nF	0.24 % + 7.8 pF		
10 Hz to 1 KHz	(11 to 32.9999) nF	0.23 % + 78 pF		
10 Hz to 1 KHz	(33 to 109.999) nF	0.24 % + 78 pF		
10 Hz to 1 KHz	(110 to 329.999) nF	0.24 % + 0.23 nF		
10 Hz to 600 Hz	(0.33 to 1.09999) μF	0.24 % + 0.8 nF		
(10 to 300) Hz	(1.1 to 3.29999) μF	0.23 % + 2.3 nF		
(10 to 150) Hz	(3.3 to 10.9999) μF	0.24 % + 7.8 nF		
(10 to 120) Hz	(11 to 32.9999) μF	0.34 % + 24 nF		
(10 to 80) Hz	(33 to 109.999) μF	0.39 % + 78 nF		
(0 to 50) Hz	(110 to 329.999) μF	0.39 % + 0.24 μF		
(0 to 20) Hz	(0.33 to 1.09999) mF	0.37 % + 0.8 μF		
(0 to 6) Hz	(1.1 to 3.2999) mF	0.37 % + 2.3 μF		
(0 to 2) Hz	(3.3 to 10.9999) mF	0.37 % + 8 μF		
(0 to 0.6) Hz	(11 to 32.9999) mF	0.59 % + 24 μF		
(0 to 0.2) Hz	(33 to 110) mF	0.86 % + 78 μF		
Electrical Simulation of Thermocouples Indicating Devices – Generate and Measure ³				
Type E	(-250 to -100) °C	0.42 °C		Fluke 5520A/SC1100
	(-100 to -25) °C	0.18 °C		
	(-25 to 350) °C	0.17 °C		
	(350 to 650) °C	0.18 °C		
	(650 to 1000) °C	0.21 °C		
Type J	(-210 to -100) °C	0.24 °C		
	(-100 to -30) °C	0.18 °C		
	(-30 to 150) °C	0.17 °C		
	(150 to 760) °C	0.18 °C		
	(760 to 1200) °C	0.22 °C		
Type K	(-200 to -100) °C	0.28 °C		
	(-100 to -25) °C	0.19 °C		
	(-25 to 120) °C	0.18 °C		
	(120 to 1000) °C	0.24 °C		
	(1000 to 1372) °C	0.33 °C		
Type T	(-250 to -150) °C	0.50 °C		
	(-150 to 0) °C	0.22 °C		
	(0 to 120) °C	0.18 °C		
	(120 to 400) °C	0.17 °C		

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Parameter/Equipment	Range	CMC ^{2,5} (±)	Comments
Oscilloscopes ³ –			
Level Sine Amp –			
50 kHz reference	10 mV to 5.0 V _(p-p)	1.8 % + 0.23 mV	Fluke 5520A/SC1100
50 kHz to 100 MHz		2.9 % + 0.23 mV	
(100 to 300) MHz		3.2 % + 0.23 mV	
(300 to 600) MHz		4.7 % + 0.23 mV	
(0.6 to 1.1) GHz		5.5 % + 0.23 mV	
Flatness –			
5 mV to 5.5 V relative to 50 kHz reference	50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz (600 to 1100) MHz	1.9 % + 78 μV 2.2 % + 78 μV 3.5 % + 78 μV 4.2 % + 78 μV	
Scope Volts –			
1 MΩ, 10 Hz to 1 kHz	1 mV to 130 V _{p-p}	0.16 % + 31 μV	
1 MΩ, (1 to 10) kHz	1 mV to 130 V _{p-p}	0.23 % + 31 μV	
50 Ω, 10 Hz to 10 kHz	1 mV to 6.6 V _{p-p}	0.23 % + 31 μV	
Time Marker Output Into 50 Ω	1 ns to 50 ms 50 ms to 5 s	2.1 μs/s (25 + 800 × t) μs	
Pulse Rise Time 0.5 V, 1 V _(p-p)	1 kHz to 10 MHz	(+30 / -100) ps	

Parameter/Equipment	Frequency	CMC ^{2,5} (±)	Comments
AC Voltage – Generate ³			
(1 to 33) mV	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.064 % + 4.7 μV 0.019 % + 4.7 μV 0.023 % + 4.7 μV 0.082 % + 4.7 μV 0.28 % + 9.3 μV 0.63 % + 39 μV	Fluke 5520A
(33 to 330) mV	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.024 % + 6.2 μV 0.013 % + 6.2 μV 0.014 % + 6.2 μV 0.029 % + 6.2 μV 0.063 % + 25 μV 0.16 % + 55 μV	
(0.33 to 3.3) V	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.024 % + 39 μV 0.014 % + 47 μV 0.017 % + 47 μV 0.025 % + 39 μV 0.056 % + 97 μV 0.2 % + 470 μV	
(3.3 to 33) V	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.025 % + 510 μV 0.014 % + 470 μV 0.02 % + 470 μV 0.03 % + 470 μV 0.072 % + 1.3 mV	
(33 to 330) V	45 Hz to 1 kHz (1 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.017 % + 1.6 mV 0.017 % + 4.7 mV 0.022 % + 4.7 mV 0.03 % + 4.7 mV 0.17 % + 39 mV	
(330 to 1020) V	45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.025 % + 7.8 mV 0.021 % + 7.8 mV 0.025 % + 7.8 mV	



Parameter/Equipment	Frequency	CMC ^{2,5} (±)	Comments
AC Voltage – Measure ³			
Up to 200 mV	(10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz	0.016 % + 4 μV 0.013 % + 4 μV 0.013 % + 2 μV 0.016 % + 4 μV 0.035 % + 8 μV 0.078 % + 20 μV	Fluke 8508A
(0.2 to 2) V	(10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz (0.3 to 1) MHz	0.013 % + 20 μV 0.011 % + 20 μV 0.08 % + 20 μV 0.013 % + 20 μV 0.023 % + 40 μV 0.059 % + 200 μV 0.31 % + 2.0 mV 1.1 % + 20 mV	
(2 to 20) V	(10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz (0.3 to 1) MHz	0.013 % + 200 μV 96 μV /V + 200 μV 85 μV /V + 200 μV 0.013 % + 200 μV 0.023 % + 400 μV 0.059 % + 2.0 mV 0.31 % + 20 mV 1.1 % + 200 mV	
(20 to 200) V	(10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz	0.013 % + 2 mV 99 μV /V + 2 mV 85 μV /V + 2 mV 0.013 % + 2 mV 0.023 % + 4 mV 0.059 % + 20 mV 0.31 % + 200 mV	
(0.2 to 1000) V	(10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (100 to 300) kHz	0.013 % + 2 mV 99 μV /V + 2 mV 85 μV /V + 2 mV 0.013 % + 2 mV 0.023 % + 4 mV 0.059 % + 20 mV 0.31 % + 200 mV	
(100 to 1000) V	(40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz	0.013 % + 20 mV 0.015 % + 20 mV 0.014 % + 20 mV 0.025 % + 40 mV 0.068 % + 0.20 V	

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Parameter/Equipment	Frequency	CMC ^{2,5} (±)	Comments
AC Current ³ – Generate			
(29 to 330) µA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1.0 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.16 % + 80 nA 0.12 % + 80 nA 0.1 % + 80 nA 0.23 % + 0.12 µA 0.62 % + 0.16 µA 1.3 % + 0.32 µA	Fluke 5520A
(0.33 to 3.3) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1.0 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.16 % + 0.12 µA 0.1 % + 0.12 µA 0.08 % + 0.12 µA 0.16 % + 0.16 µA 0.41 % + 0.24 µA 0.8 % + 0.48 µA	
(3.3 to 33) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1.0 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.14 % + 1.6 µA 0.071 % + 1.6 µA 0.034 % + 1.6 µA 0.064 % + 1.6 µA 0.17 % + 2.4 µA 0.32 % + 3.2 µA	
(33 to 330) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1.0 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.14 % + 16 µA 0.071 % + 16 µA 0.034 % + 16 µA 0.079 % + 40 µA 0.16 % + 78 µA 0.32 % + 0.16 mA	
(0.33 to 1.1) A	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1.0 kHz (1 to 5) kHz (5 to 10) kHz	0.14 % + 78 µA 0.039 % + 78 µA 0.039 % + 78 µA 0.47 % + 0.78 mA 2.0 % + 4 mA	
(1.1 to 3) A	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1.0 kHz (1 to 5) kHz (5 to 10) kHz	0.14 % + 78 µA 0.15 % + 78 µA 0.055 % + 78 µA 0.47 % + 0.78 mA 2.0 % + 4 mA	
(3 to 11) A	45 Hz to 1.0 kHz (1 to 5) kHz	0.083 % + 1.6 mA 2.4 % + 1.6 mA	
(11 to 20.5) A	45 Hz to 1.0 kHz (1 to 5) kHz	0.12 % + 4 mA 2.4 % + 4 mA	

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Parameter/Equipment	Frequency	CMC ^{2,5} (±)	Comments
AC Current – Generate ³ Clamp Meters Up to 500 A (500 to 1000) A	(45 to 440) Hz (45 to 440) Hz	0.37 % + 0.1 A 0.4 % + 0.2 A	Fluke 5500A/coil & 5520A LCOMP OFF
AC Current – Measure ³ Up to 200 µA 200 µA to 2 mA (2 to 20) mA (20 to 200) mA 200 mA to 2 A (2 to 20) A	10 Hz to 10 kHz 10 Hz to 10 kHz 10 Hz to 10 kHz 10 Hz to 10 kHz 10 Hz to 2 kHz (2 to 10) kHz 10 Hz to 2 kHz (2 to 10) kHz	0.037 % + 20 nA 0.032 % + 200 nA 0.033 % + 2 µA 0.032 % + 20 µA 0.063 % + 200 µA 0.09 0% + 200 µA 0.084 % + 2 mA 0.26 % + 2 mA	Fluke 8508A

II. Electrical – RF / Microwave

Parameter/Equipment	Frequency	CMC ² (±)	Comments
RF Power – Generate ³ (13 to -5) dB (-20 to -58) dB (-50 to -80) dB (+20 to -100) dBm	200 Hz to 80 MHz 2.5 MHz to 26.5 GHz	0.09 dB 0.13 dB 0.25 dB 0.6 dB	HP 3335A HP 83630B synthesizer w/8902; 11722A, 11792A sensors, 1793A converter

Parameter/Equipment	Frequency	CMC ² (±)	Comments
RF Power – Measure ³			
0 dBm	50 MHz	0.39 % rdg	HP 432A, 478A-H76, 8508A
(-20 to +30) dBm	100 kHz to 1.3 GHz (0.05 to 26.5) GHz	0.063 dB + 1 digit 0.13 dB +1 digit	Agilent 8902A Receiver w/11793A converter, Agilent 11722A / 11792A
RF Tuned Power/Attenuation – Measure ³			
(0 to -10) dB	(2.5 to 1300) MHz	0.035 dB + 1 digit	Agilent 8902A Receiver w/11722A
(-10 to -20) dB		0.04 dB + 1 digit	
(-20 to -30) dB		0.045 dB + 1 digit	
(-30 to -40) dB		0.051 dB + 1 digit	
(-40 to -50) dB		0.058 dB + 1 digit	
(-50 to -60) dB		0.058 dB + 1 digit	
(-60 to -70) dB		0.064 dB + 1 digit	
(-70 to -80) dB		0.07 dB + 1 digit	
(-80 to -90) dB		0.076 dB + 1 digit	
(-90 to -100) dB		0.083 dB + 1 digit	
(-100 to -110) dB	(1.3 to 26.5) GHz	0.14 dB + 1 digit	Agilent 8902A Receiver w/11793A converter, Agilent 11722A / 11792A
(-110 to -120) dB		0.19 dB + 1 digit	
(0 to -10) dB		0.035 dB + 1 digit	
(-10 to -20) dB		0.04 dB + 1 digit	
(-20 to -30) dB		0.045 dB + 1 digit	
(-30 to -40) dB		0.051 dB + 1 digit	
(-40 to -50) dB		0.058 dB + 1 digit	
(-50 to -60) dB		0.058 dB + 1 digit	
(-60 to -70) dB	0.14 dB + 1 digit		
(-70 to -80) dB	0.19 dB + 1 digit		
(-80 to -100) dB	0.25 dB + 1 digit		



Parameter/Equipment	Frequency	CMC ^{2,5} (±)	Comments
Amplitude Modulation – Measure ³			
Rate: 50 Hz to 10 kHz Depth: (5 to 99) %	150 kHz to 10 MHz	2.4 % + 1 digit	Agilent 8902A Receiver w/ 11722A
Rate: 20 Hz to 10 kHz Depth: Up to 99 %	150 kHz to 10 MHz	3.5 % + 1 digit	
Rate: 50 Hz to 10 kHz Depth: (5 to 99) %	(10 to 1300) MHz	1.4 % + 1 digit	
Rate: 20 Hz to 10 kHz Depth: Up to 99 %	(10 to 1300) MHz	3.6 % + 1 digit	
Frequency Modulation – Measure ³			
Rate: 20 Hz to 10 kHz Dev.: ≤ 40 kHz peak	250 kHz to 10 MHz	2.3 % + 1 digit	Agilent 8902A measuring receiver w/ 11715A test source
Rate: 50 Hz to 100 kHz Dev.: ≤ 400 kHz peak	(10 to 1300) MHz	1.2 % + 1 digit	
Rate: 20 Hz to 200 kHz Dev.: ≤ 400 kHz peak	(10 to 1300) MHz	5.8 % + 1 digit	

III. Mechanical

Parameter/Equipment	Range	CMC ² (±)	Comments
Torque – Wrenches & Drivers ³	(5 to 50) ozf·in (10 to 100) ozf·in (5 to 50) lbf·in (50 to 500) lbf·in (25 to 250) lbf·ft	0.77 % Indicated Value 0.77 % Indicated Value 0.77 % Indicated Value 0.77 % Indicated Value 0.77 % Indicated Value	Check-line ITI and ITF-System



IV. Time & Frequency

Parameter/Equipment	Range	CMC ^{2, 4} (\pm)	Comments
Frequency – Measuring Equipment ³			
Rubidium Standard	5, 10 MHz	$(5.2 \times 10^{-10}) \text{ Hz} + 0.58R$	Stanford Research FS725
	Up to 80 MHz Up to 26.5 GHz	$(5.2 \times 10^{-10}) \text{ Hz} + 1 \mu\text{Hz}$ $(8.1 \times 10^{-10}) \text{ Hz} + 0.58R$	Rubidium, Agilent 33250A & 83630B
Frequency – Measure ³	Up to 12.4 GHz	$(5.2 \times 10^{-10}) \text{ Hz}$	Rubidium, Agilent 53132A

¹ This laboratory offers commercial calibration and field calibration service.

² Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

³ Field calibration service is available for this calibration and this laboratory meets A2LA R104 – *General Requirements: Accreditation of Field Testing and Field Calibration Laboratories* for these calibrations. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.

⁴ In the statement of CMC, L is the numerical value of the nominal length of the device measured in inches or millimeters. In the statement of CMC, R is the numerical value of the resolution of the device.

⁵ The stated measured values are determined using the indicated instrument (see Comments). This capability is suitable for the calibration of the devices intended to measure or generate the measured value in the ranges indicated. CMC's are expressed as either a specific value that covers the full range or as a percent or fraction of the reading plus a fixed floor specification.





Accredited Laboratory

A2LA has accredited

SIMCO ELECTRONICS

Scottsdale, AZ

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCSLI Z540-1-1994 and the requirements of ANSI/NCSLI Z540.3-2006 and any additional program requirements in the field of calibration. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009*).



Presented this 22nd day of December 2015.

A handwritten signature in black ink, reading "Peter Abney".

President & CEO
For the Accreditation Council
Certificate Number 1395.22
Valid to September 30, 2017

For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.